Application/Control No. Applicant(s)/Patent Under Reexamination 10/822,898 CLAY ET AL. Notice of References Cited Art Unit Examiner Page 1 of 1 2179 Ba Huynh **U.S. PATENT DOCUMENTS Document Number** Date Classification Name Country Code-Number-Kind Code MM-YYYY Wakabayashi et al. US-5,903,634 05-1999 379/127.01 Α US-2003/0200159 10-2003 Kay et al. 705/28 В * US-2004/0100479 05-2004 Nakano et al. 345/700 С * US-2003/0117365 06-2003 D Shteyn, Yevgeniy Eugene 345/156 * US-2002/0041292 04-2002 Son et al. Ε 345/810 US-F US-G USн US-1 US-US-Κ US-L US-М FOREIGN PATENT DOCUMENTS Document Number Date Country Name Classification Country Code-Number-Kind Code MM-YYYY Ν 0 Р Q R s T **NON-PATENT DOCUMENTS** Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) U ٧

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